

COIN TRUNK CIRCUIT SD-32539-01
ARRANGED FOR DIAL-TONE-FIRST SERVICE
OPERATION TESTS
USING TRUNK TEST SET SD-90469-01 OR
SD-90469-02 (J94710A)
STEP-BY-STEP SYSTEMS

1. GENERAL

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1.01 This section describes a method of testing the operating features of the coin trunk SD-32539-01, arranged for dial-tone-first service, using trunk test set SD-90469-01 or SD-90469-02 (J94710A). Information in this section was formerly contained in Section 226-521-500.

the coin trunk while under a leak condition.

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1.02 This section is reissued for the following reasons:

D. Operator Cut-Through and Ringback: This test checks the metallic cut-through over which the operator controls the coin and also the feature that provides the operator with a means of holding a trunk and ringing back through it.

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(a) To revise paragraph 1.05 to include information about sleeve identification when performing Test D in offices equipped with ANI

E. Stuck-Coin Alarm Test: This test checks that the stuck-coin alarm feature of the coin trunk functions satisfactorily.

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(b) To add Test G to test the 12-second disconnect feature (option ZF).

F. Coin-Trunk-Timed-Release Circuit Test (SD-31861-01): This test checks that the coin-trunk-timed-release circuit will release the coin trunk when a stuck-coin condition is applied.

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This issue affects the Equipment Test List.

1.03 The tests covered are:

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A. Coin Test: This test checks the ability of the coin trunk circuit to recognize that a coin has not been deposited.

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B. Coin Collect—Loop: This test checks the coin collect features of the coin trunk while under a loop condition.

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C. Coin Return—Leak: This test checks the coin return features of

G. 12-Second Forced Disconnect Feature (Option ZF): This test checks the 12-second forced disconnect feature (option ZF) which disconnects the switch train within 12 seconds when the called party disconnects but coin station remains off-hook.

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1.04 These tests should preferably be made during periods of light traffic, and the performance of Test C should be coordinated with the group responsible for operator services.

NOTICE

Not for use or disclosure outside the
Bell System except under written agreement

SECTION 226-521-508

1.05 During Test C, when testing to a TSPS office, and automatic number identification (ANI) equipment is provided in the testing office, a sleeve identification will have to be provided to prevent second trial transverter failure registrations. (See Fig. 1 for example of providing this sleeve identification.)

1.06 When testing coin trunks equipped with coin-trunk-timed-release circuit (SD-31861-01), test each trunk in accordance with procedures of Test E; then test each trunk in accordance with procedures of Test F.

1.07 During Test F, the check of the coin-trunk-timed-release circuit register, if provided, will cause the register to advance. The reporting of this register operation should be in accordance with local instructions.

1.08 When making the coin-trunk-timed-release circuit (SD-31861-01) ineffective in an office arranged for extending alarms to another office, operate audible alarm switch or key to position where audible alarms will be heard. For offices not arranged for extending alarms, at coin-trunk-timed-release circuit (SD-31861-01), turn CO key to a position where GD lamp lights. Some offices may have circuit arrangements which do not furnish key control. In this case, it will be necessary to block coin-trunk-timed-release C relay in the nonoperated position.

1.09 When making the coin-trunk-timed-release circuit (SD-31861-01) effective in an office arranged for extending alarms to another office,

operate audible alarm switch or key to position that makes alarms extend to another office. Notify proper person in the distant office that alarms have been transferred. For offices not arranged for extending alarms, at coin-trunk-timed-release circuit (SD-31861-01), turn CO key to a position where GD lamp is extinguished.

1.10 When testing coin trunks which are reached through secondary line switches, the key, which is provided at the trunk relay rack for rotating the secondary master switch associated with the trunk to be tested, should be operated momentarily to pick up disengaged plungers.

2. TEST PROCEDURES

A. Apparatus

Tests A Through G

2.01 Trunk test set J94710A (SD-90469-01 or SD-90469-02) equipped with ZH and ZK options which provide an RCK key and CTCK lamp.



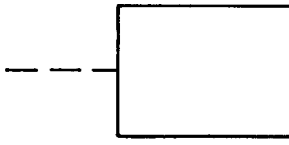

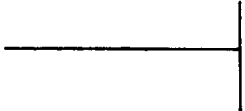

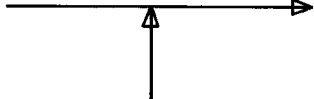
2.02 Head telephone set, 52-type.

2.03 Two P3E patching cords, 6 feet long, equipped with red-shelled 310 plugs (3P7A cords).

B. Flowcharts

2.04 Table A provides an explanation of the symbols that are used in the test procedure flowcharts.

TABLE A
FLOW CHART EXPLANATIONS

SYMBOL	EXPLANATION
	<p>Indicates the beginning of the procedure and an exit or entrance reference to pages within same procedure.</p>
	<p>Indicates an action which is performed on a manual or automatic basis.</p>
	<p>Brackets are used to reference supporting-type data.</p>
	<p>Used to represent a decision which determines which one of two paths to take.</p>
	<p>The end of procedure symbol is used to denote that the end of the emergency action condition has been completed.</p>
	<p>Used to indicate the direction of information flow.</p>
	<p>Used to indicate two processes flowing into a common sequence.</p>

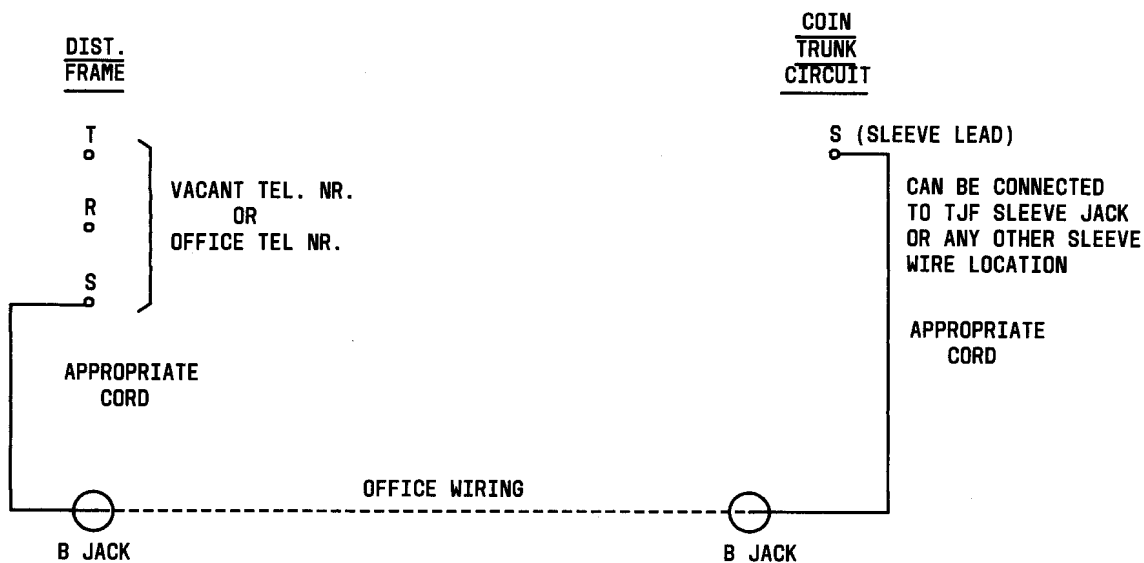


Fig. 1—Example of Connections Needed for Test D When Office is Equipped With ANI

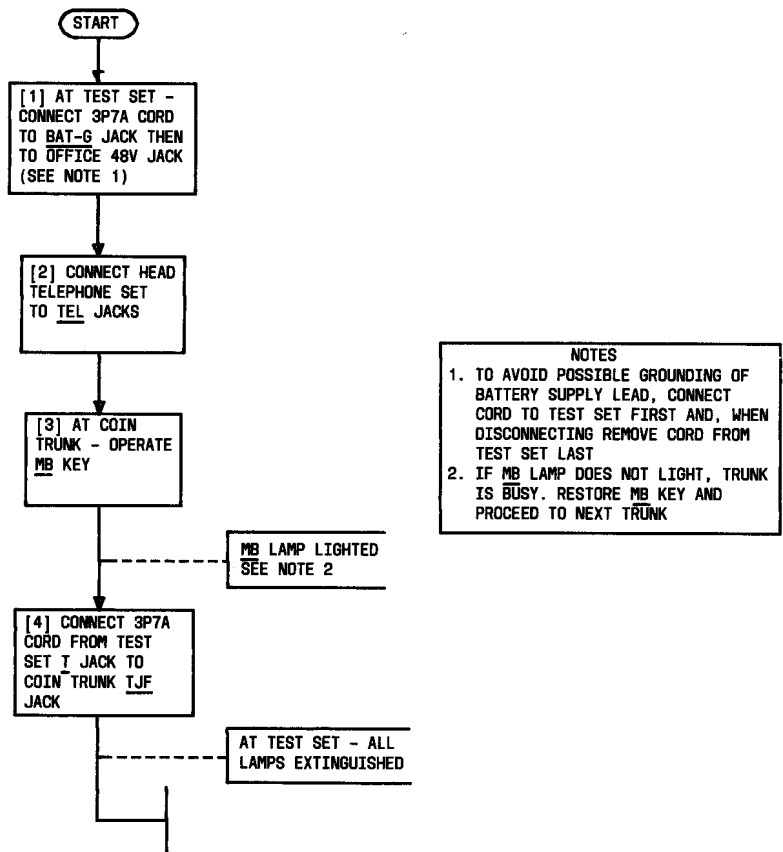


Fig. 2—Test Preparation

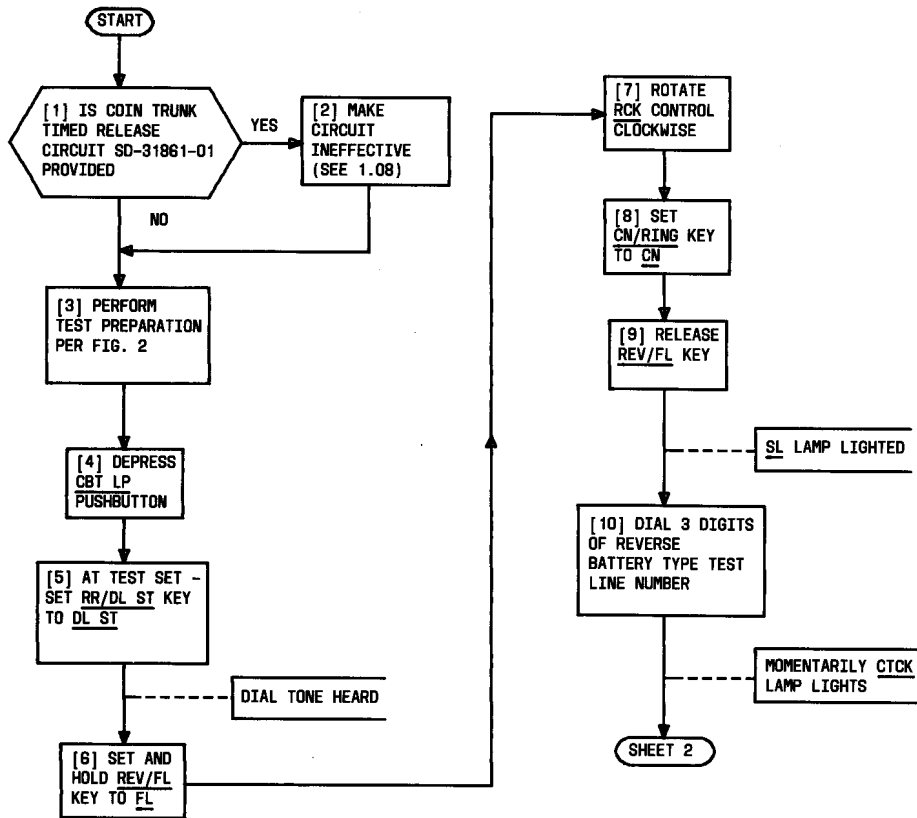


Fig. 3—Test A: Coin Test (Sheet 1 of 3)

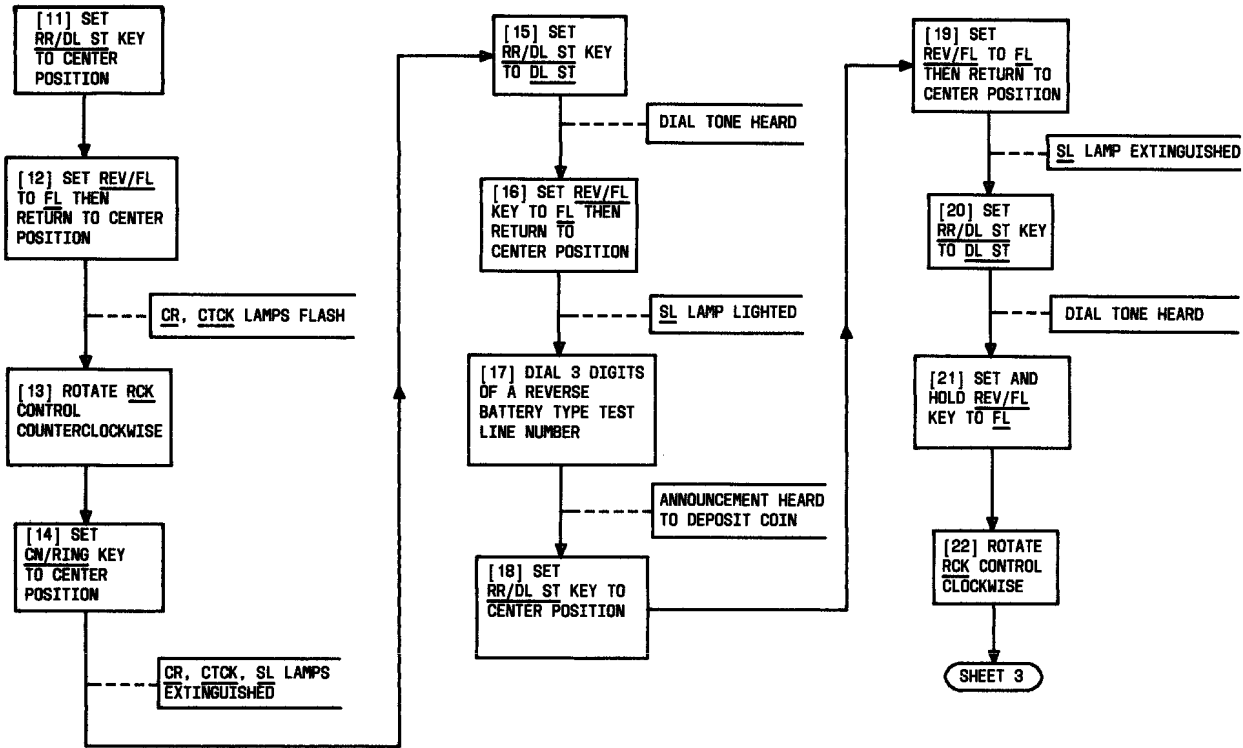


Fig. 3—Test A: Coin Test (Sheet 2 of 3)

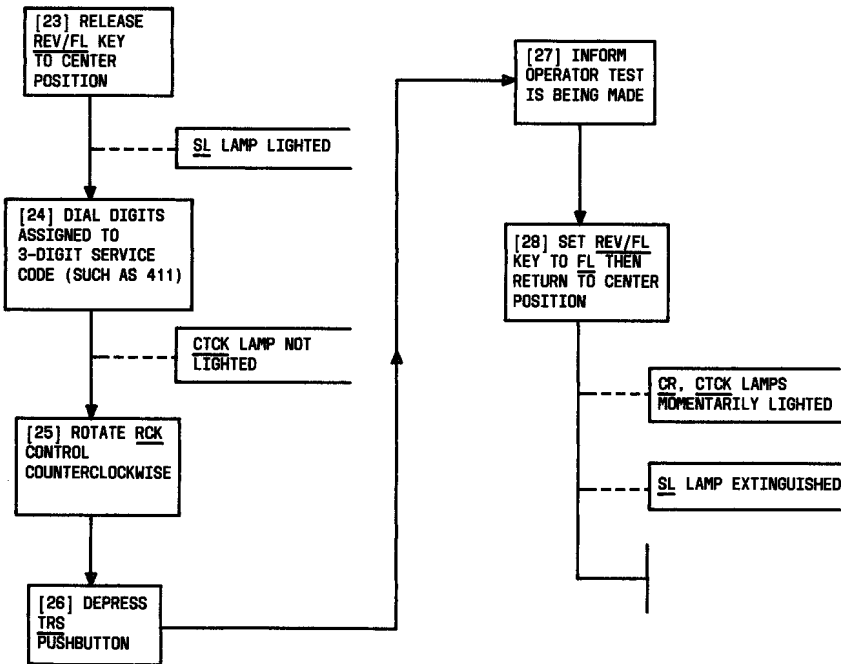


Fig. 3—Test A: Coin Test (Sheet 3 of 3)

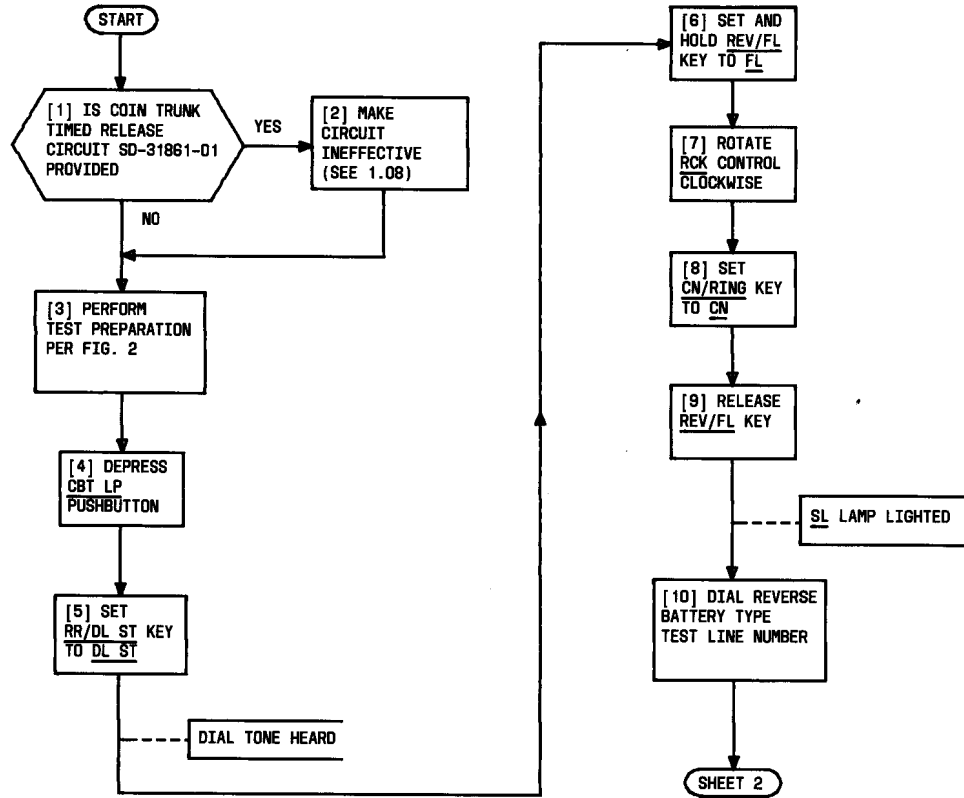


Fig. 4—Test B: Coin Collect-Loop (Sheet 1 of 2)

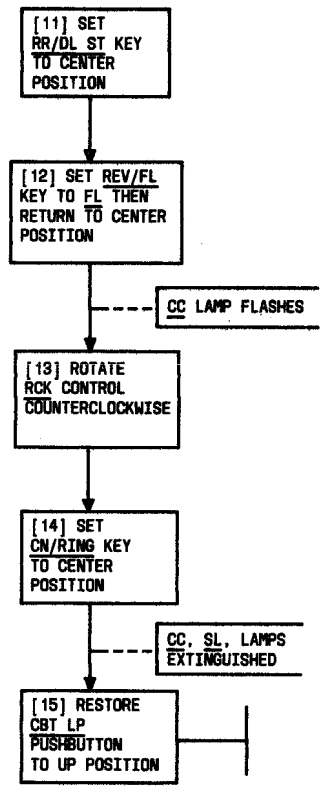


Fig. 4—Test B: Coin Collect-Loop (Sheet 2 of 2)

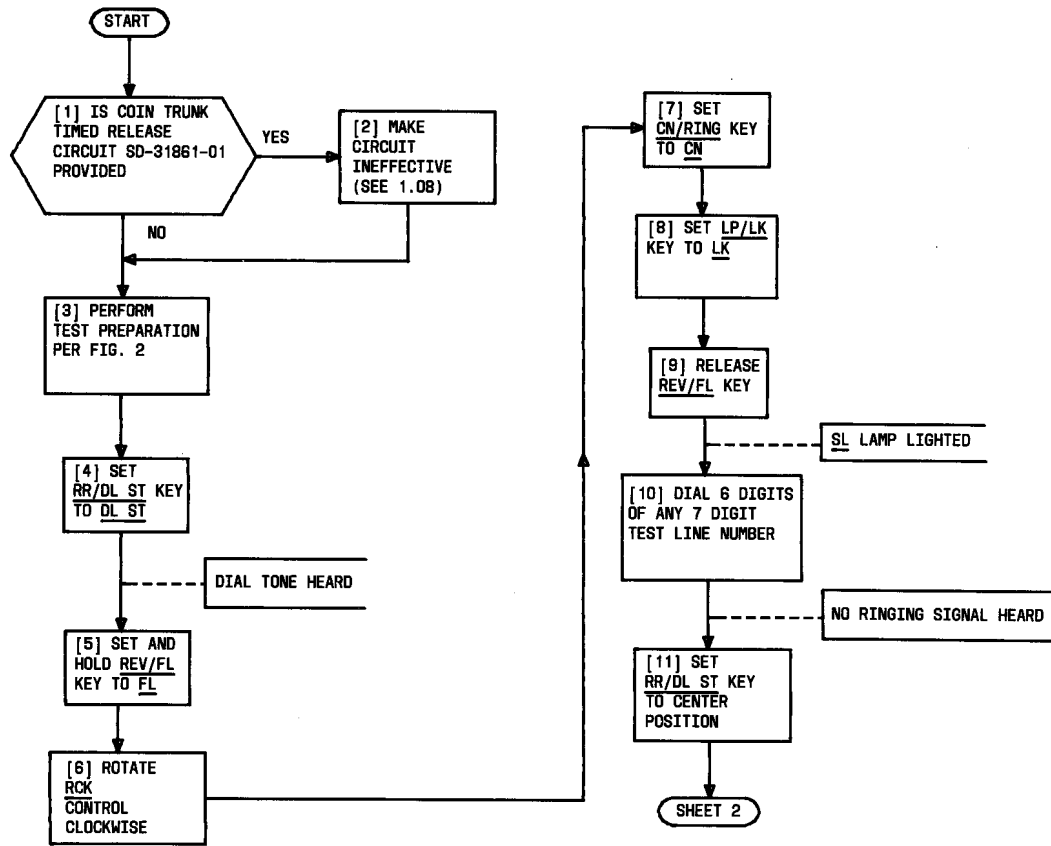


Fig. 5—Test C: Coin Return-Leak (Sheet 1 of 2)

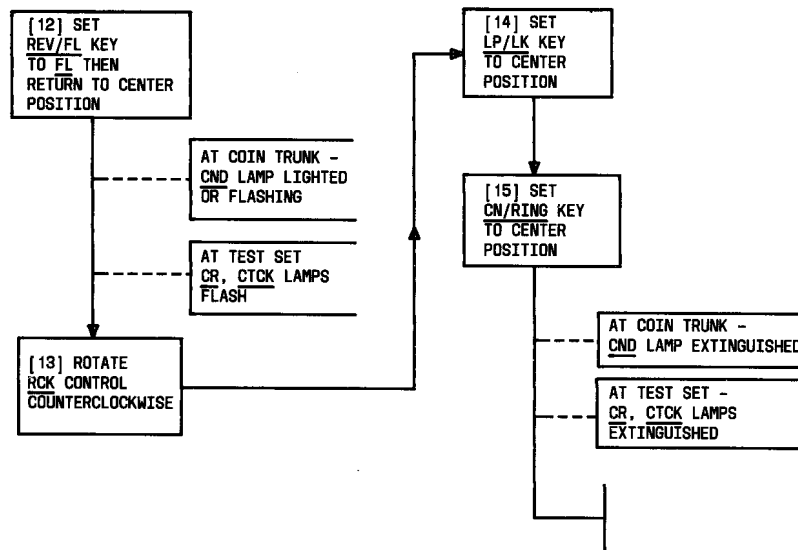


Fig. 5—Test C: Coin Return-Leak (Sheet 2 of 2)

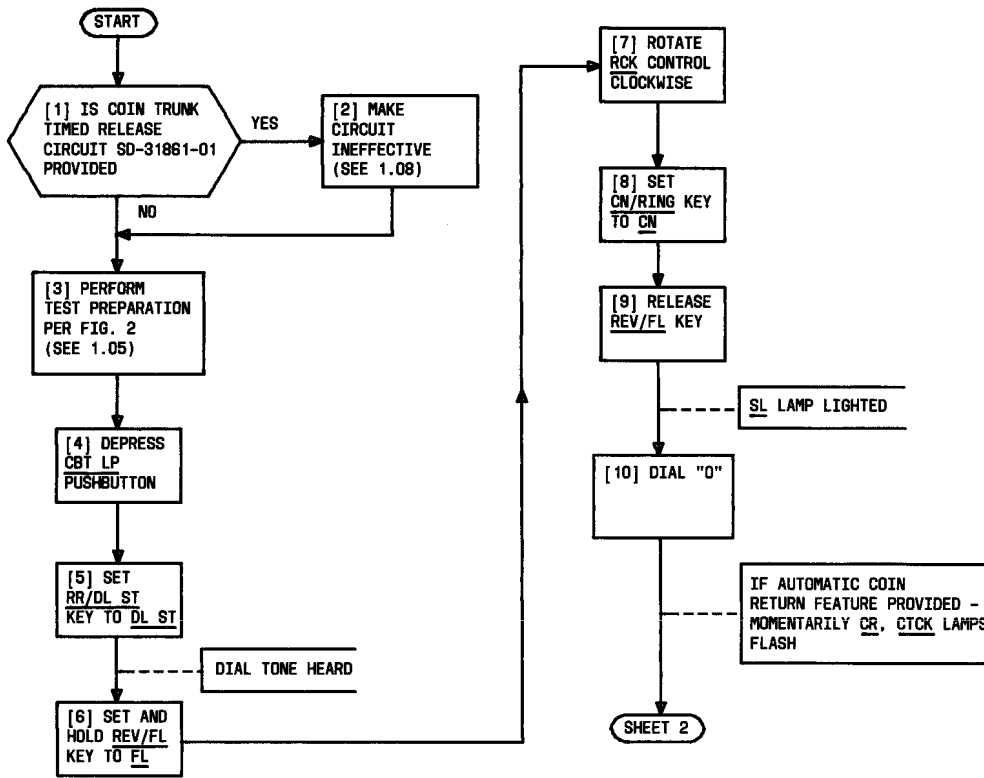


Fig. 6—Test D: Operator Cut-Through and Ringback (Sheet 1 of 3)

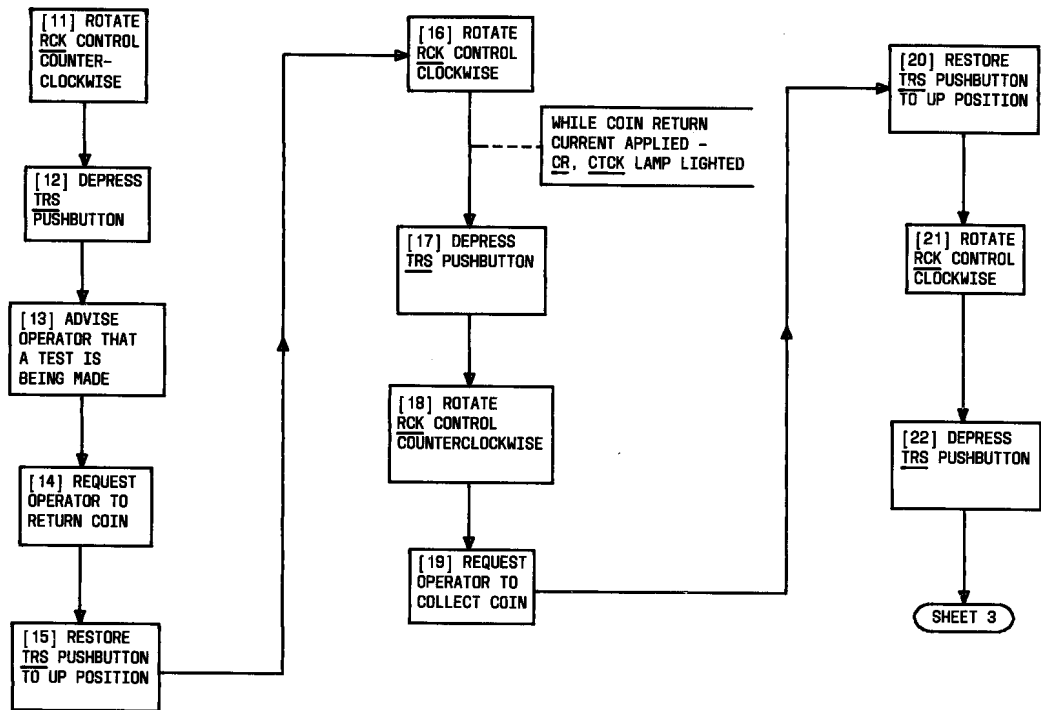


Fig. 6—Test D: Operator Cut-Through and Ringback (Sheet 2 of 3)

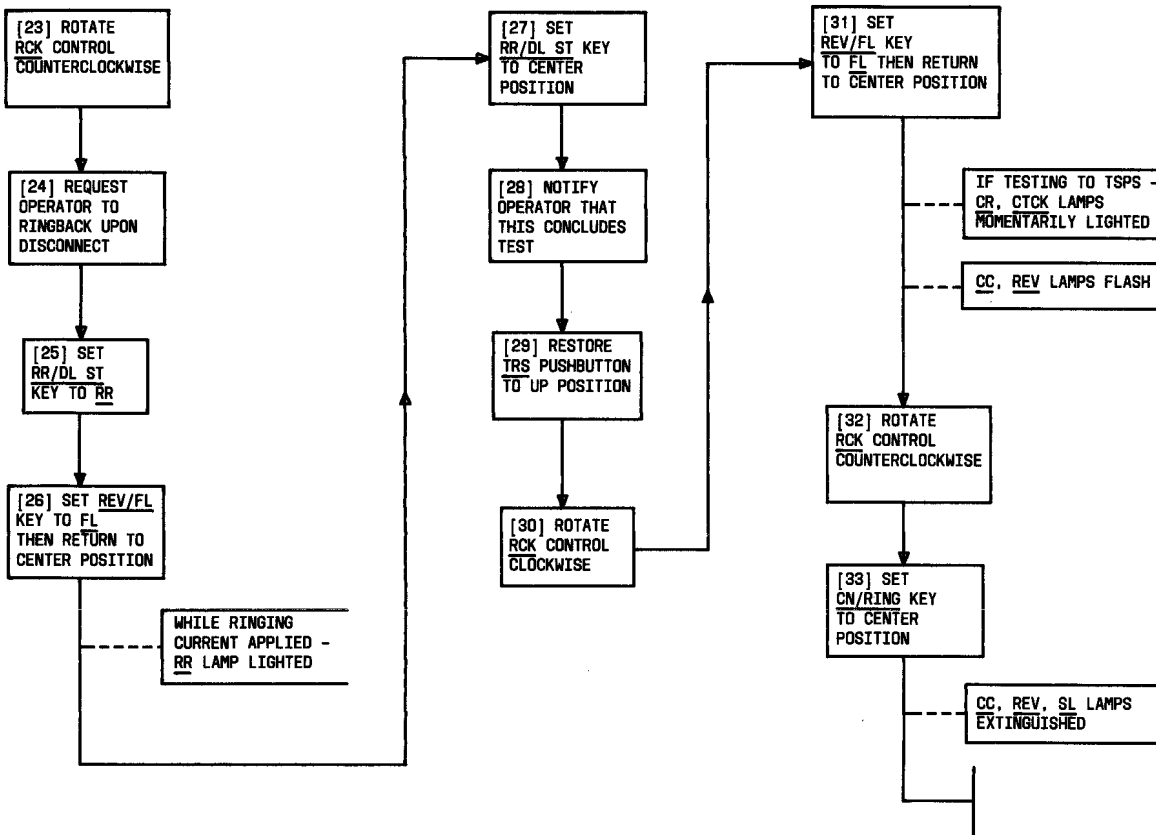


Fig. 6—Test D: Operator Cut-Through and Ringback (Sheet 3 of 3)

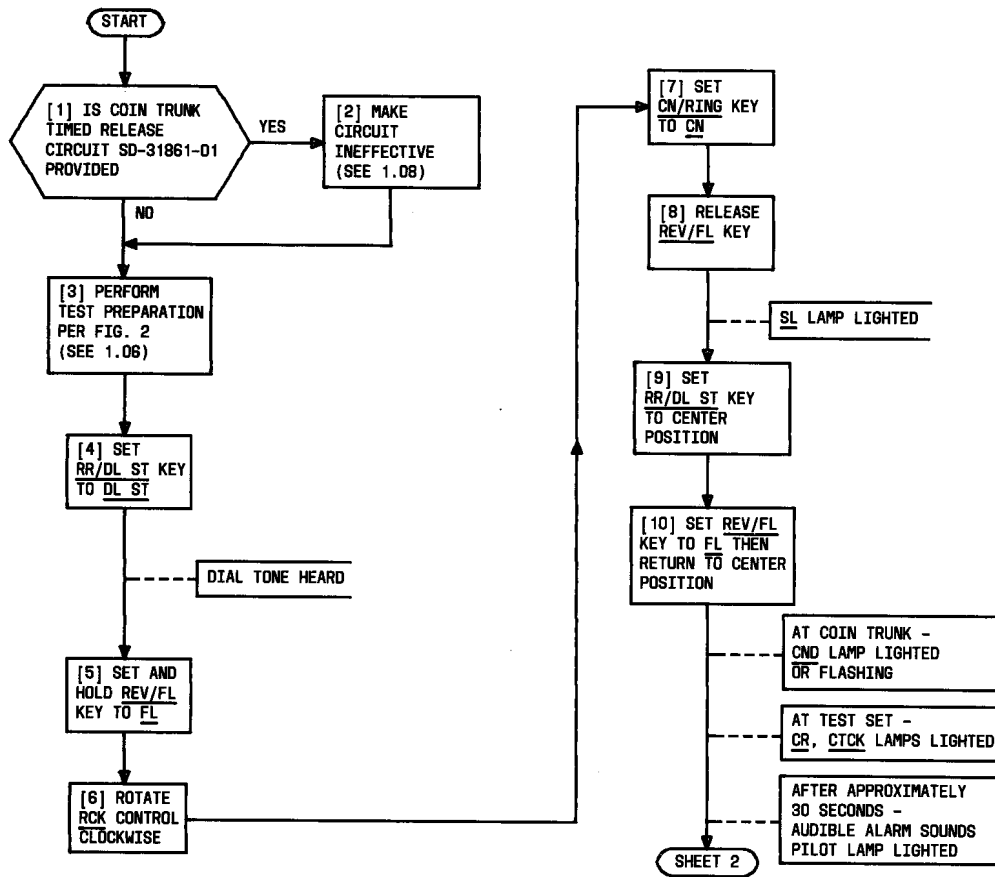


Fig. 7—Test E: Stuck-Coin Alarm Test (Sheet 1 of 2)

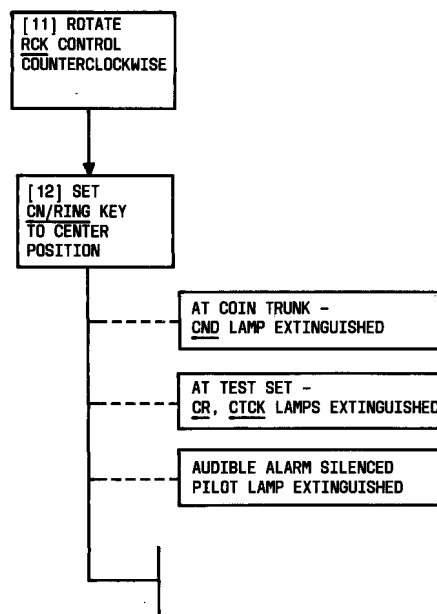


Fig. 7—Test E: Stuck-Coin Alarm Test (Sheet 2 of 2)

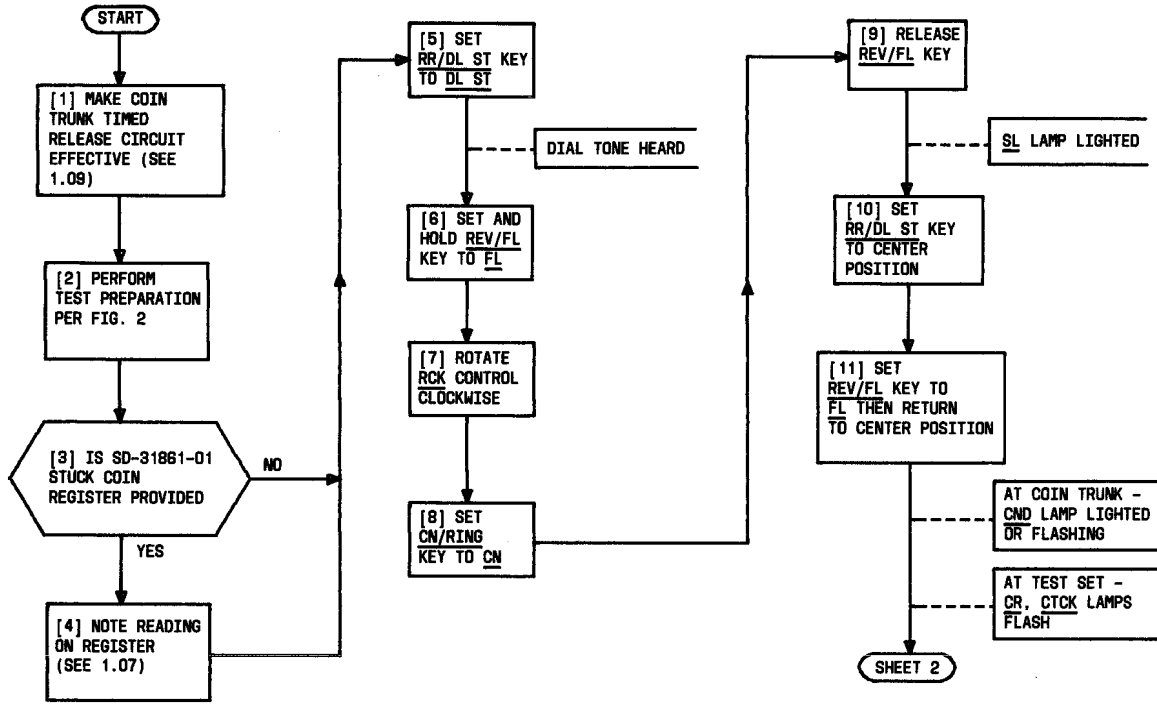


Fig. 8—Test F: Coin-Trunk-Timed-Release Circuit Test (SD-31861-01) (Sheet 1 of 2)

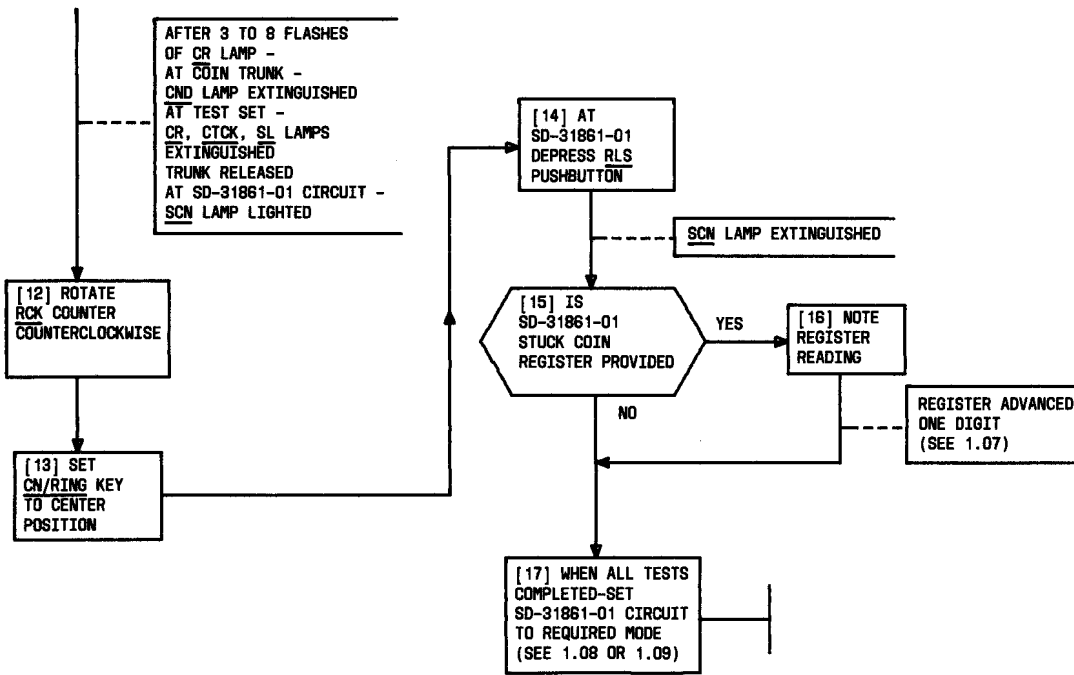


Fig. 8—Test F: Coin-Trunk-Timed-Release Circuit Test (SD-31861-01) (Sheet 2 of 2)

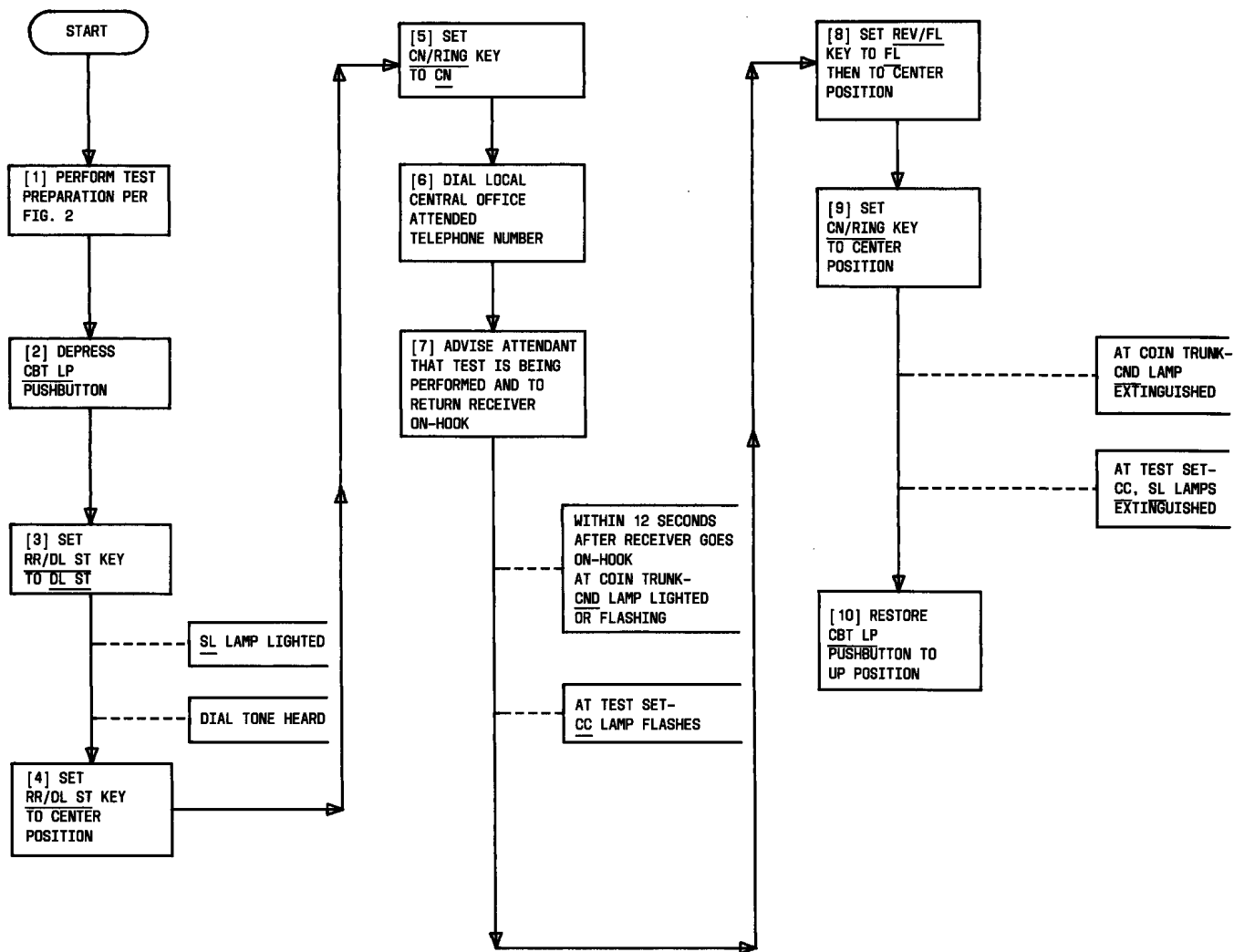


Fig. 9—Test G: 12-Second Forced Disconnect Feature (Option ZF)